

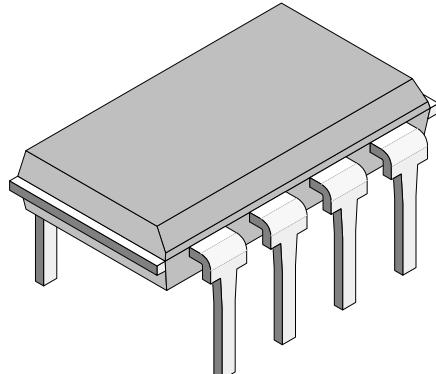
Silicon PIN Photodiode Array

Description

S268P is a silicon PIN photodiode array in a inline configuration.

Three single photodiode chips with a common cathode are mounted in a waterclear 8 pin dual in line package.

Each chip measures 3mm by 3mm and provides a radiant sensitive area of 7.5 mm².



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Features

- Three photodiodes with common cathode
- Fast response times
- Small junction capacitance
- High photo sensitivity
- Large radiant sensitive area ($A = 3 \times 7.5 \text{ mm}^2$)
- Wide angle of half sensitivity $\phi = \pm 65^\circ$
- Suitable for visible and near infrared radiation

Applications

High speed and high sensitive PIN photodiode array for industrial applications, measuring and control

Absolute Maximum Ratings $T_{amb} = 25^\circ C$

Parameter	Test Conditions	Symbol	Value	Unit
Reverse Voltage		V_R	60	V
Power Dissipation	$T_{amb} \leq 25^\circ C$	P_V	215	mW
Junction Temperature		T_j	100	$^\circ C$
Storage Temperature Range		T_{stg}	-55...+100	$^\circ C$
Soldering Temperature	$t \leq 3$ s, mounted on plated, printed board	T_{sd}	260	$^\circ C$
Thermal Resistance Junction/Ambient		R_{thJA}	350	K/W

Basic Characteristics (Single Diode) $T_{amb} = 25^\circ C$

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
Breakdown Voltage	$I_R = 100 \mu A, E = 0$	$V_{(BR)}$	60			V
Reverse Dark Current	$V_R = 10 V, E = 0$	I_{ro}		2	30	nA
Diode Capacitance	$V_R = 0 V, f = 1 MHz, E = 0$	C_D		70		pF
Diode Capacitance	$V_R = 3 V, f = 1 MHz, E = 0$	C_D		25	40	pF
Open Circuit Voltage	$E_e = 1 mW/cm^2$	V_o		350		mV
Temp. Coefficient of V_o	$E_e = 1 mW/cm^2$	TK_{V_o}		-2.6		mV/K
Short Circuit Current	$E_A = 1 klx$	I_k		70		μA
Short Circuit Current	$E_e = 1 mW/cm^2, \lambda = 950 nm$	I_k		47		μA
Temp. Coefficient of I_k	$E_A = 1 mW/cm^2, \lambda = 950 nm$	TK_{Ik}		0.1		%/K
Reverse Light Current	$E_A = 1 klx, V_R = 5 V$	I_{ra}		75		μA
Reverse Light Current	$E_e = 1 mW/cm^2, \lambda = 950 nm, V_R = 5 V$	I_{ra}	40	50		μA
Reverse Light Current Ratio of Two Diodes					1:1.2	
Angle of Half Sensitivity		ϕ		± 65		deg
Wavelength of Peak Sensitivity		λ_p		900		nm
Range of Spectral Bandwidth		$\lambda_{0.5}$		600...1050		nm
Noise Equivalent Power	$V_R=10V, \lambda=950nm$	NEP		4×10^{-14}		W/ \sqrt{Hz}
Rise Time	$V_R=10V, R_L=1k\Omega, \lambda=820nm$	t_r		100		ns
Fall Time	$V_R=10V, R_L=1k\Omega, \lambda=820nm$	t_f		100		ns

Typical Characteristics ($T_{amb} = 25^\circ C$ unless otherwise specified)

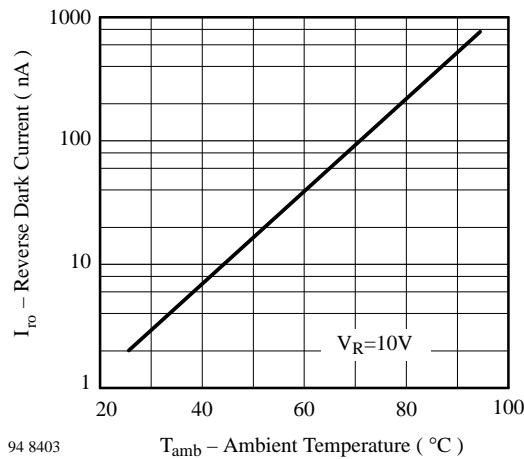


Figure 1 : Reverse Dark Current vs. Ambient Temperature

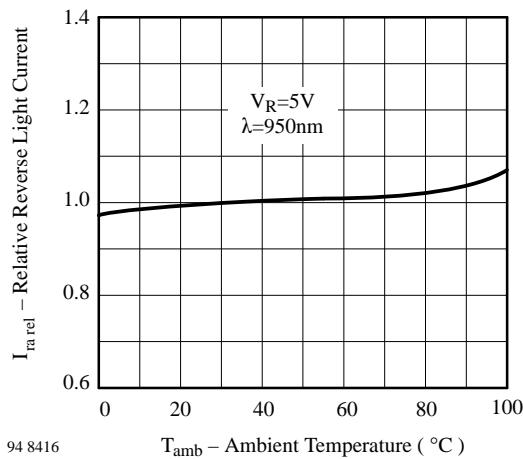


Figure 2 : Relative Reverse Light Current vs. Ambient Temperature

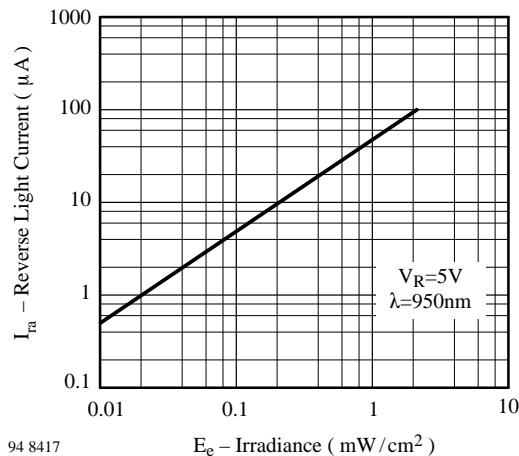


Figure 3 : Reverse Light Current vs. Irradiance

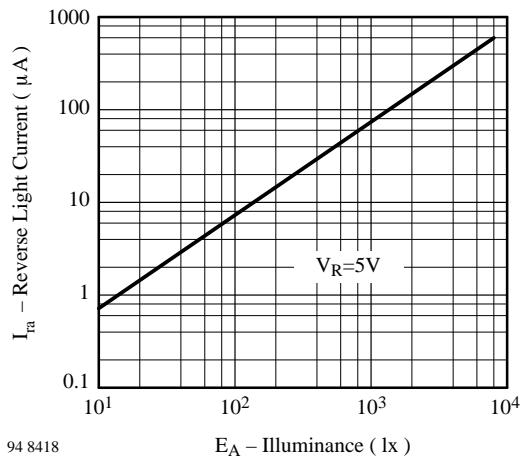


Figure 4 : Reverse Light Current vs. Illuminance

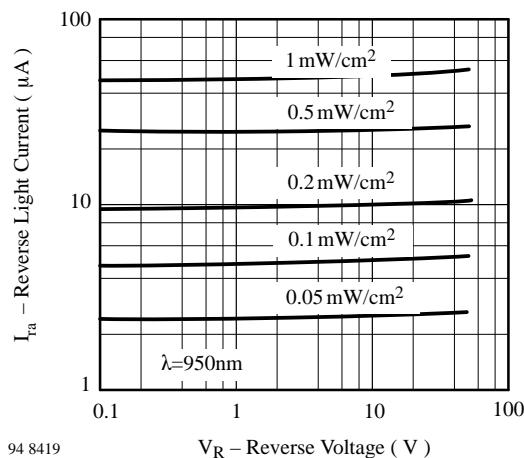


Figure 5 : Reverse Light Current vs. Reverse Voltage

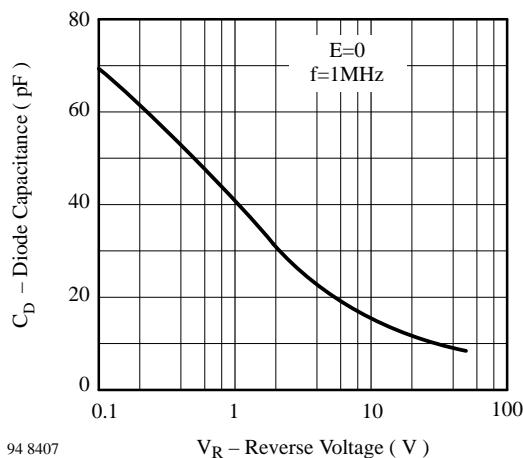
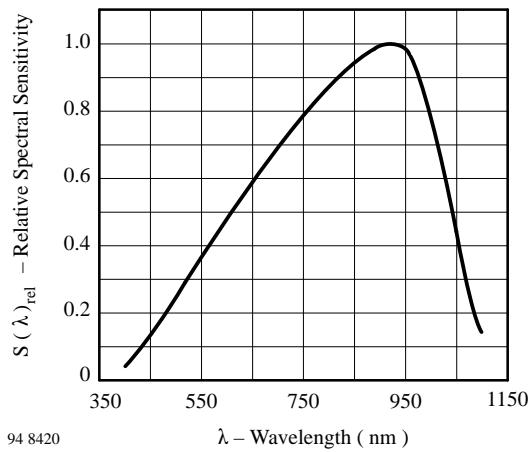


Figure 6 : Diode Capacitance vs. Reverse Voltage

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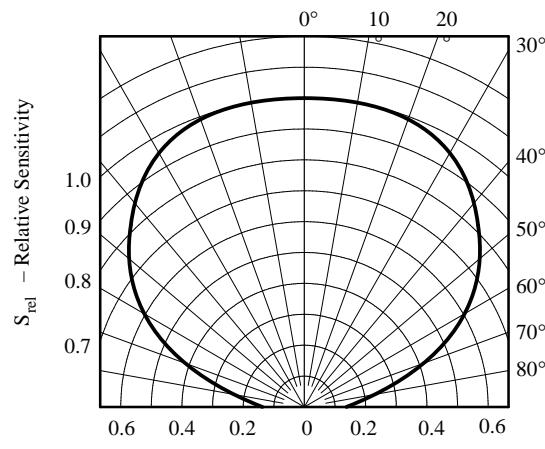
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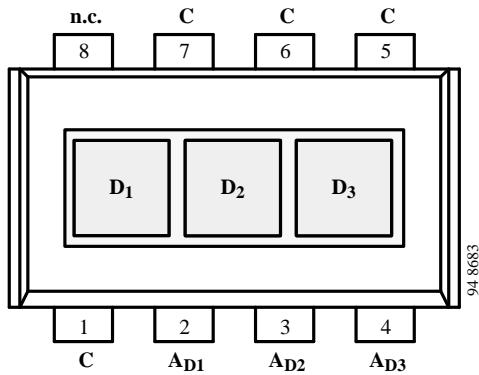
λ – Wavelength (nm)

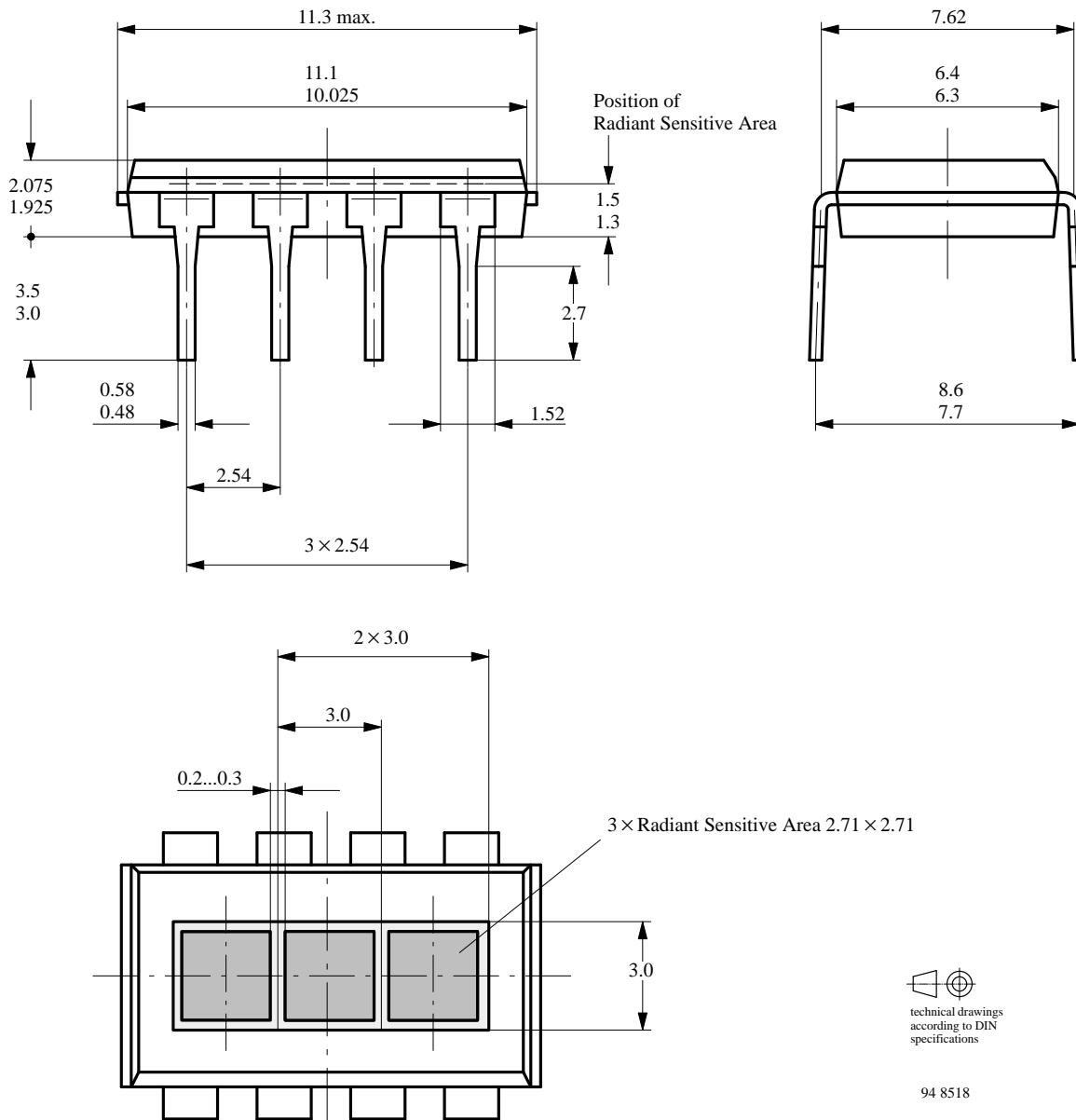
Figure 7 : Relative Spectral Sensitivity vs. Wavelength



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Figure 8 : Relative Radiant Sensitivity vs. Angular Displacement



Dimensions in mm

We reserve the right to make changes to improve technical design without further notice.

Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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